



MEYER BURGER

# High<sup>LIGHT</sup> Module Tester

## System Certification



中国计量科学研究院  
National Institute of Metrology, China

The High<sup>LIGHT</sup> module tester is the newest module tester in the product portfolio of Meyer Burger. The high quality light source is equal to Pasan's well market-proven SunSim family, and a huge improvement has been done on the Electronic load. Its accuracy is twice better and it is designed to generate dynamic sweep used for DragonBack<sup>®</sup>. Moreover, the new user-friendly software platform drives the High<sup>LIGHT</sup> system by using Measurement Process approach that automatically optimizes parameters to maximize the measurement accuracy.

This High<sup>LIGHT</sup> sun simulator manufactured by Pasan SA has been tested and validated by the National Institute of Metrology (NIM) Beijing. Beside an evaluation of the electronic load's accuracy and the light source quality, the DragonBack<sup>®</sup> method has been validated. This special measurement method has been developed in order to measure high capacitive modules. The National Institute of Metrology (NIM) Beijing certifies that:

### Pasan's High<sup>LIGHT</sup> electronic load provides highly accurate current and voltage measurements

#### Delta NIM measurement vs High<sup>LIGHT</sup> electronic load measurement:

- Isc raw: < 0.21%
- Voc raw: < 0.07%

### Pasan's High<sup>LIGHT</sup> light source provides an A+A+A+ light quality.

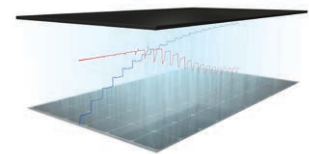
#### Results measured at NIM:

- Spectrum: < +/- 12.5%
- Uniformity: 0.43%
- LTI (10ms): 0.25%

### Pasan's DragonBack<sup>®</sup>

The DragonBack<sup>®</sup> measurement is a suitable method for measuring high-capacitive modules with A+ light quality, alternatively to a continuous light system which warm up the module during the measurement. Test results shows that a Pmax measured by DragonBack remains within +/- 0.1% compared to a multflash direct/reverse measurement.

All relevant measurements have been carried out at the laboratory of the National Institute of Metrology (NIM) at Beijing in January 2015 and the results are documented in a test report.



We reserve the right to make changes reflecting technical progress (04/2015)